

X-Ray Polarimetry Detectors @ XCF (X-ray calibration facility)

Simone Maldera



XCF: X-ray Calibration Facility @Torino

Irradiation setup in Torino, to test, characterize and qualify

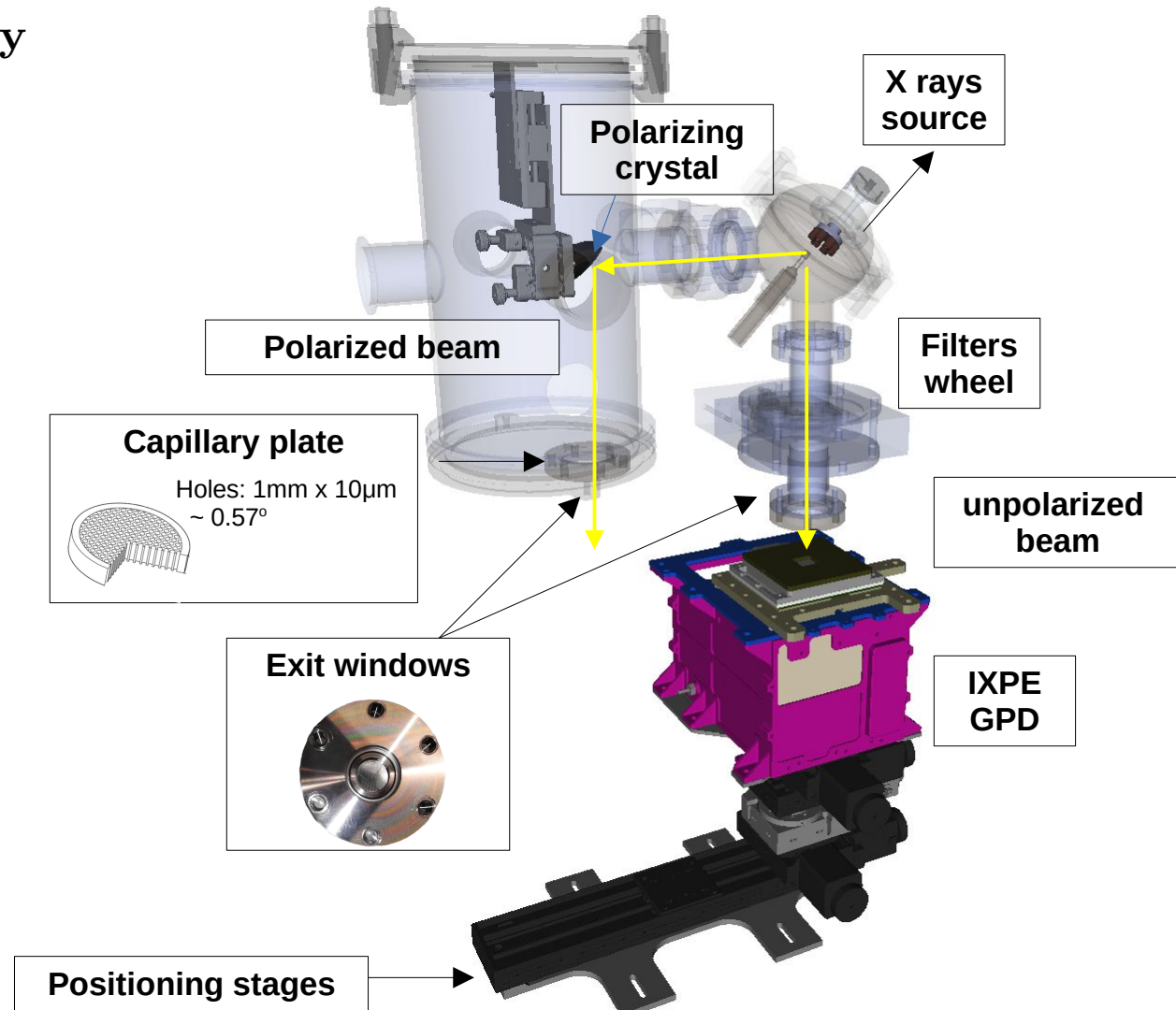
- Gas Pixel Detectors
- Position- energy- and **polarization**-sensitive X-ray detectors.



XCF: X-ray Calibration Facility

Main Characteristics:

- Multi-anode Xray source
- two output beams, one polarized
- Crystal positioning:
 - height
 - θ , φ axes
- Detector positioning:
 - Two couples x-y stages
 - One rotary stage
- Source and polarizer cylinder in vacuum ($\sim 10^{-6}$ hPa)



X-ray source: McPherson 462

Specifications

6 interchangeable solid anodes

Flux in bright lines: $\sim 10^{11}$ photons s^{-1} sr^{-1}

Emission uniformity: Dual beam output, balanced

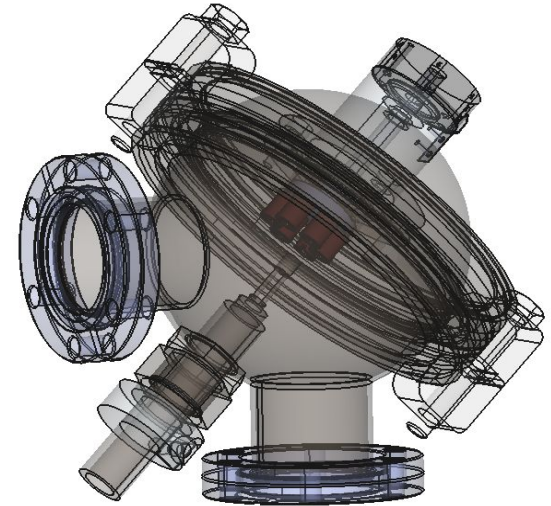
Power: 30W, 10 kV max, 3mA

Operating pressure: 10^{-6} torr range or lower

Selected anodes:

Anode	Mo	Rh	Pd	Ti	Fe	Ni
Line	L α	L α	L α	K α	K α	K α
E [KeV]	2.293	2.697	2.839	4.511	6.404	7.478

We control manually both voltage and anode current



Beam monitors

- Amptec fast SDD



25 mm² active area

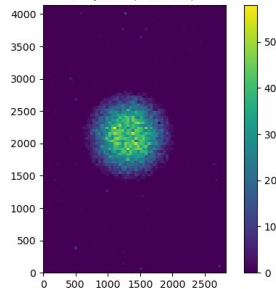
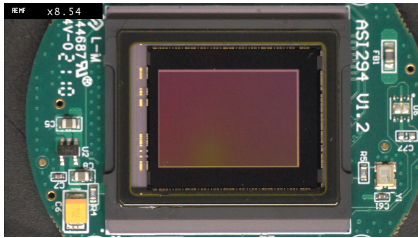
Resolution of 122 eV FWHM at 5.9 keV ~2%

Count rates > 1,000,000 CPS

Windows: Be 12.5 μm

- Modified* optical sensor (sony IMX294)

*glass cover removed

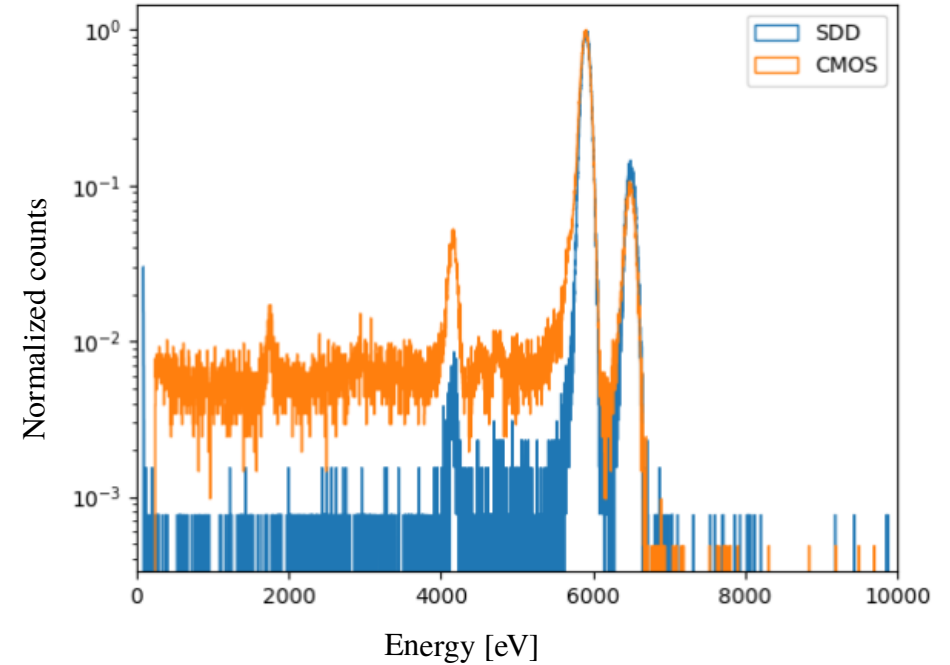


4144x2822 pixels (4.63 μm)

Energy resolution (FWHM) ~2.2% @6keV

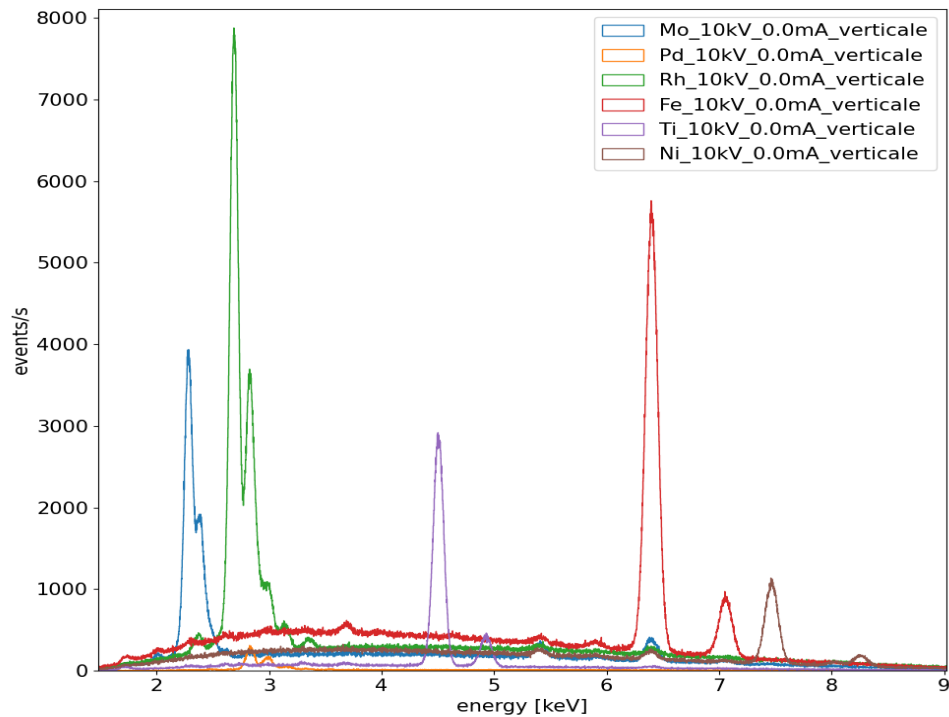
Efficiency ~10% @6keV w.r.t SDD

⁵⁵Fe energy spectrum



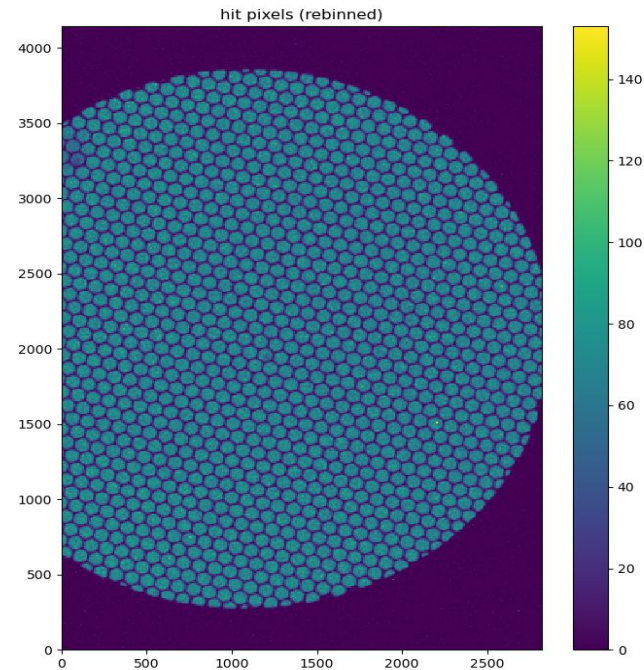
X-ray source: measured output

Energy:



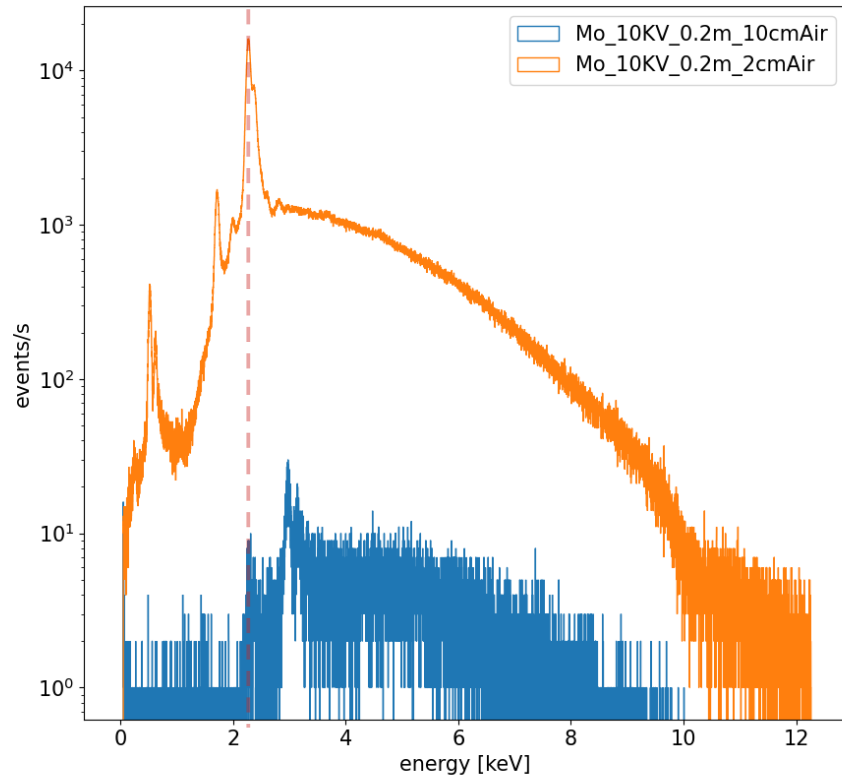
Measured with Ampek fast SDD

Spatial uniformity

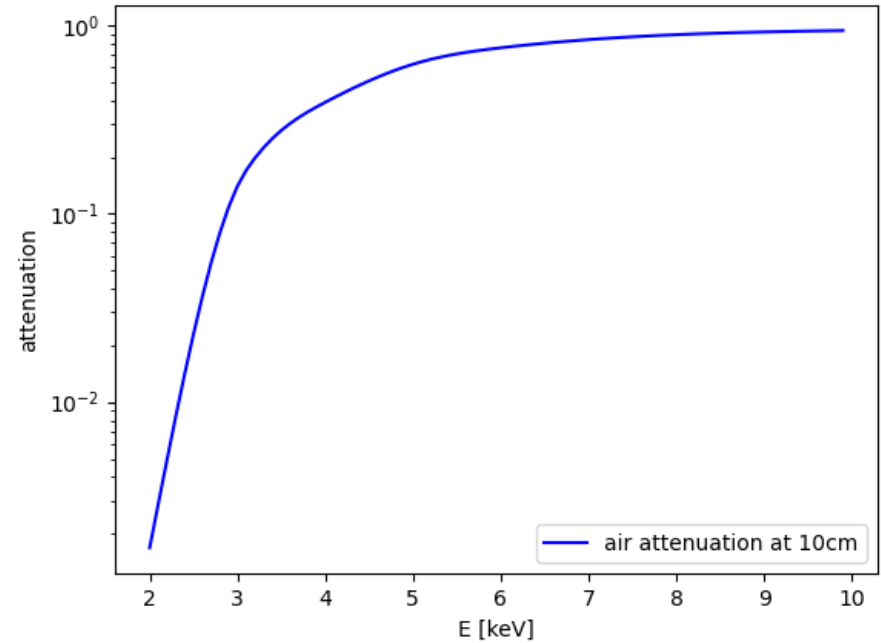


Measured with sony cmos

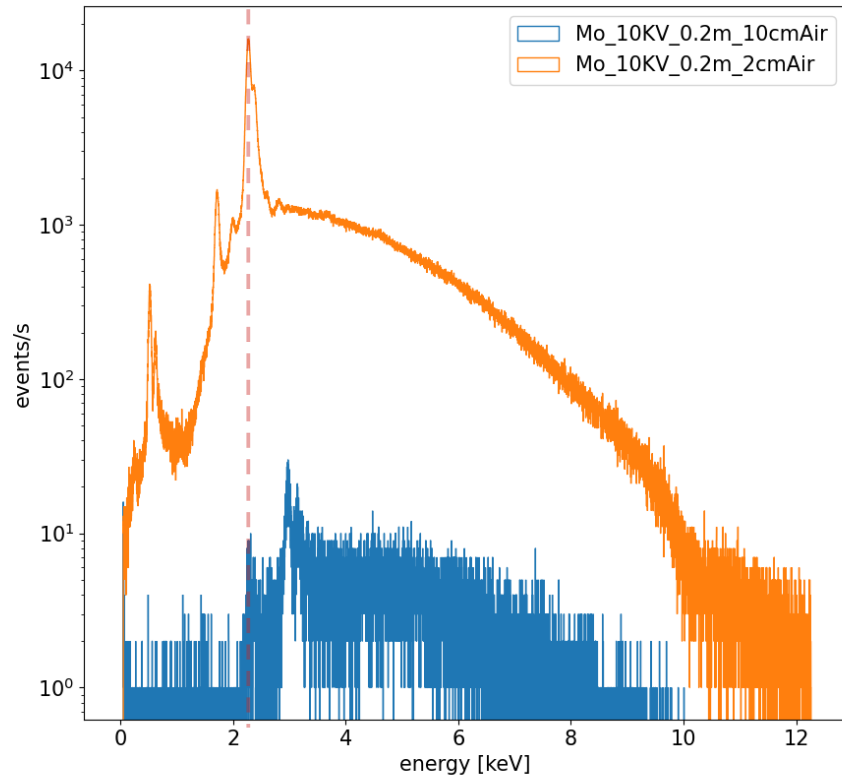
Air attenuation:



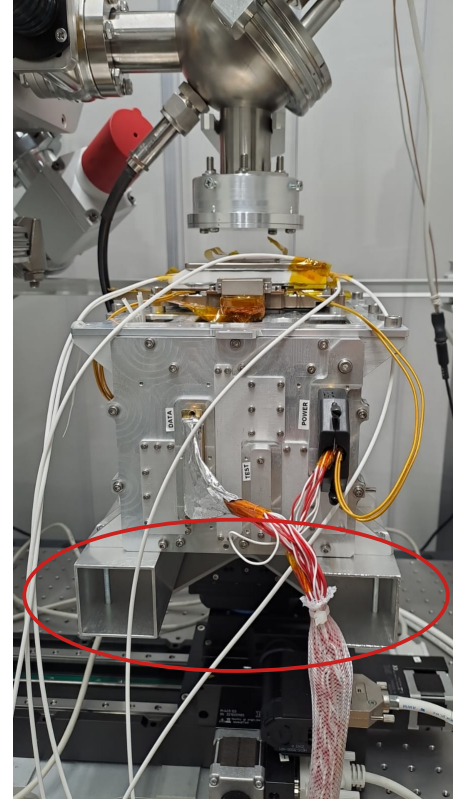
At low energy air attenuation is important!



Air attenuation:



At low energy air attenuation is important!



We need to keep the detector as close as possible to the exit window

Polarization by Bragg diffraction at 45°

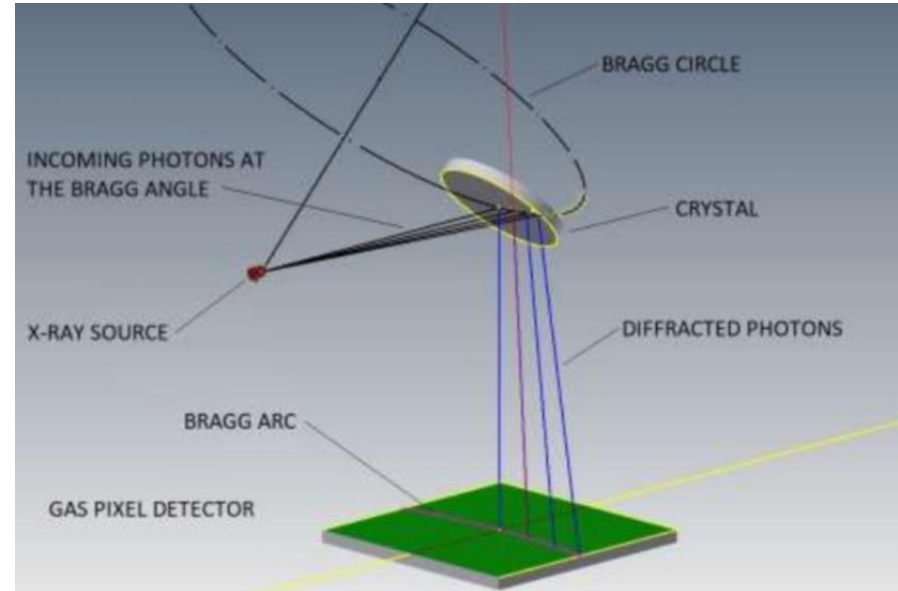
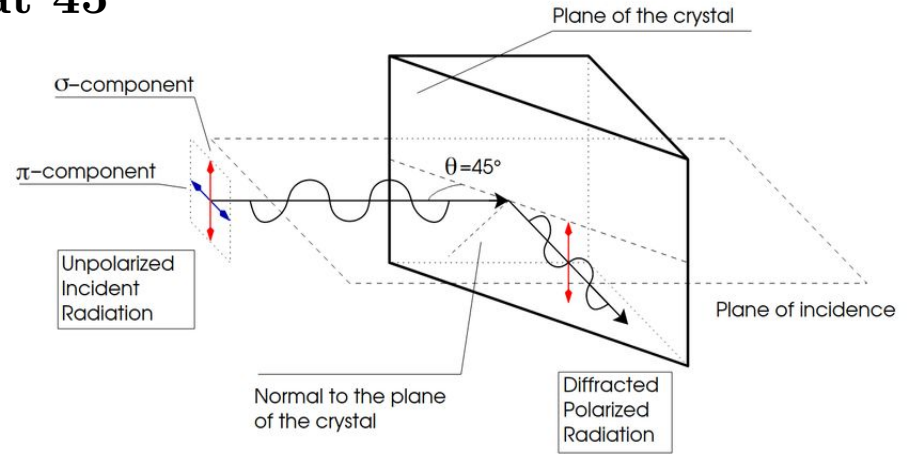
Bragg condition

$$\sin(\theta_{\text{Bragg}}) = \frac{nhc}{2dE}$$

Polarization degree:

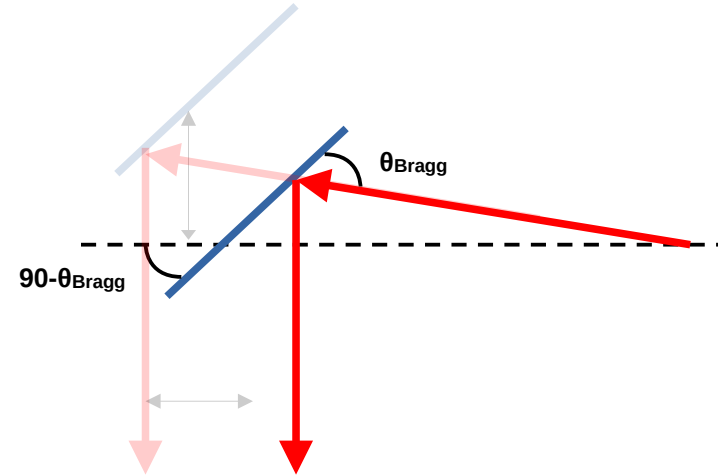
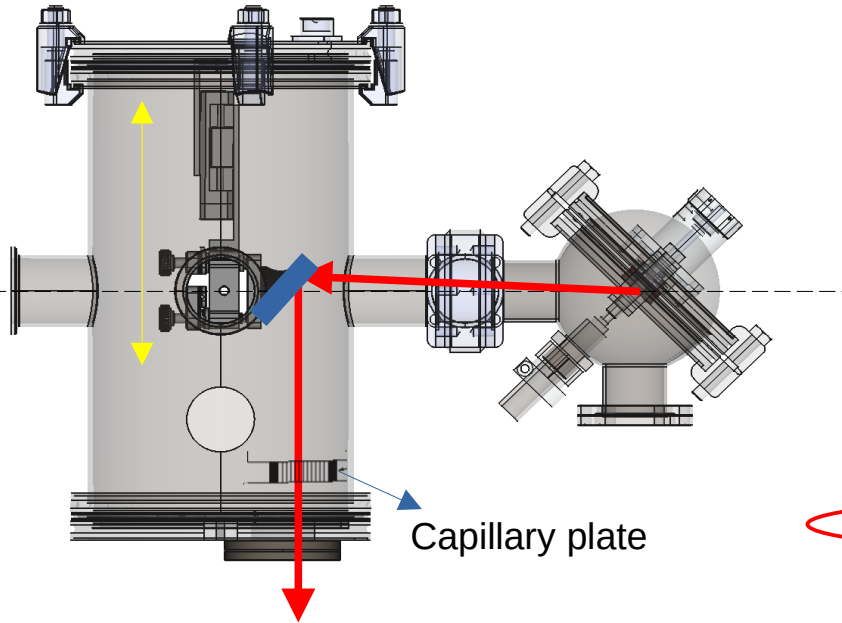
$$\mathcal{P} = \frac{1 - k}{1 + k}$$

With: $k = \frac{R^\pi}{R^\sigma} \approx 0$ for $\theta_{\text{Bragg}} \approx 45^\circ$



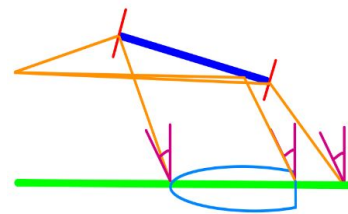
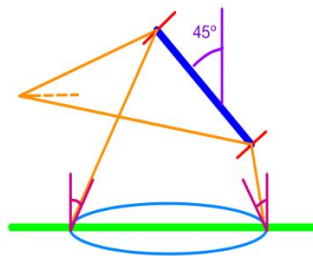
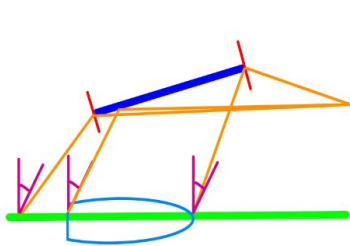
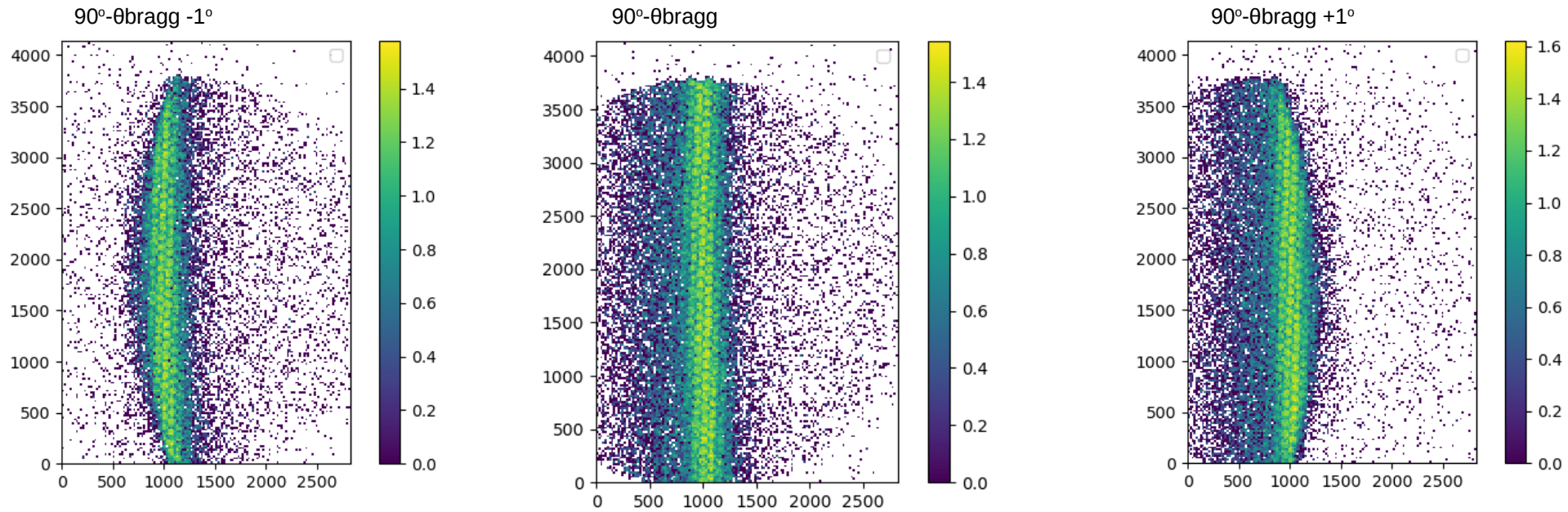
Polarized beam

selecting vertical output with capillary plate, the geometry is fixed



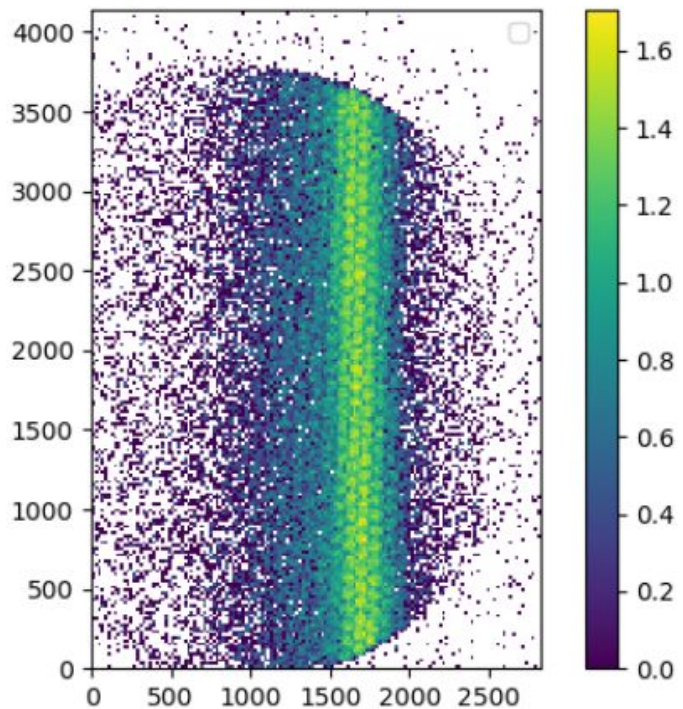
Anode line	E [KeV]	Xtal	2d (A)	θ_{Bragg}	P
Mo $L\alpha$	2.2932	InSb111	7.481	46.28	99.32%
Rh $L\alpha$	2.697	Ge111	6.532	44.87	99.28%
Pd $L\alpha$	2.839	Si111	6.271	44.12	>95.08%
Ti $K\alpha$	4.511	Si 220	3.840	45.71	99.51%
Fe $K\alpha$	6.404	Si 400	2.7142	45.5	99.7% ??
Ni $k\alpha$	7.478	Ge 422	2.31	45.86	99.04%

InSb111 xtal positionig: angle

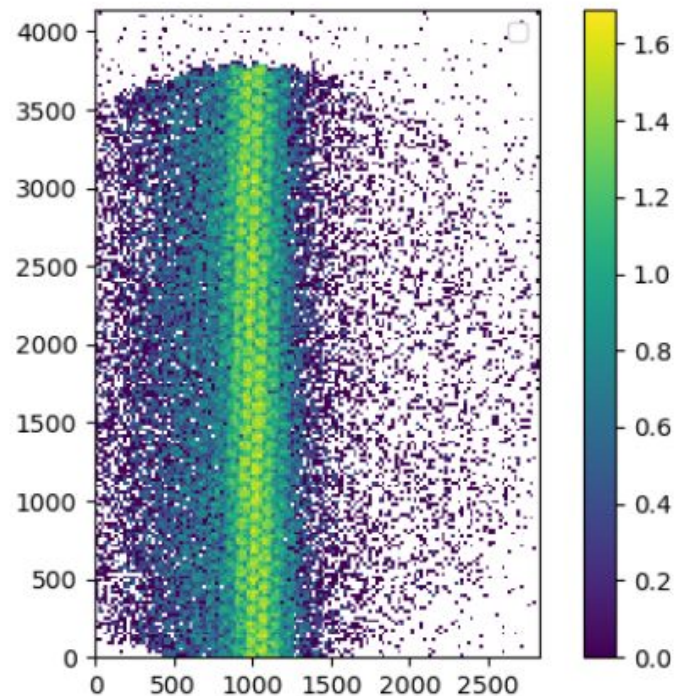


InSb111 xtal positionig: height

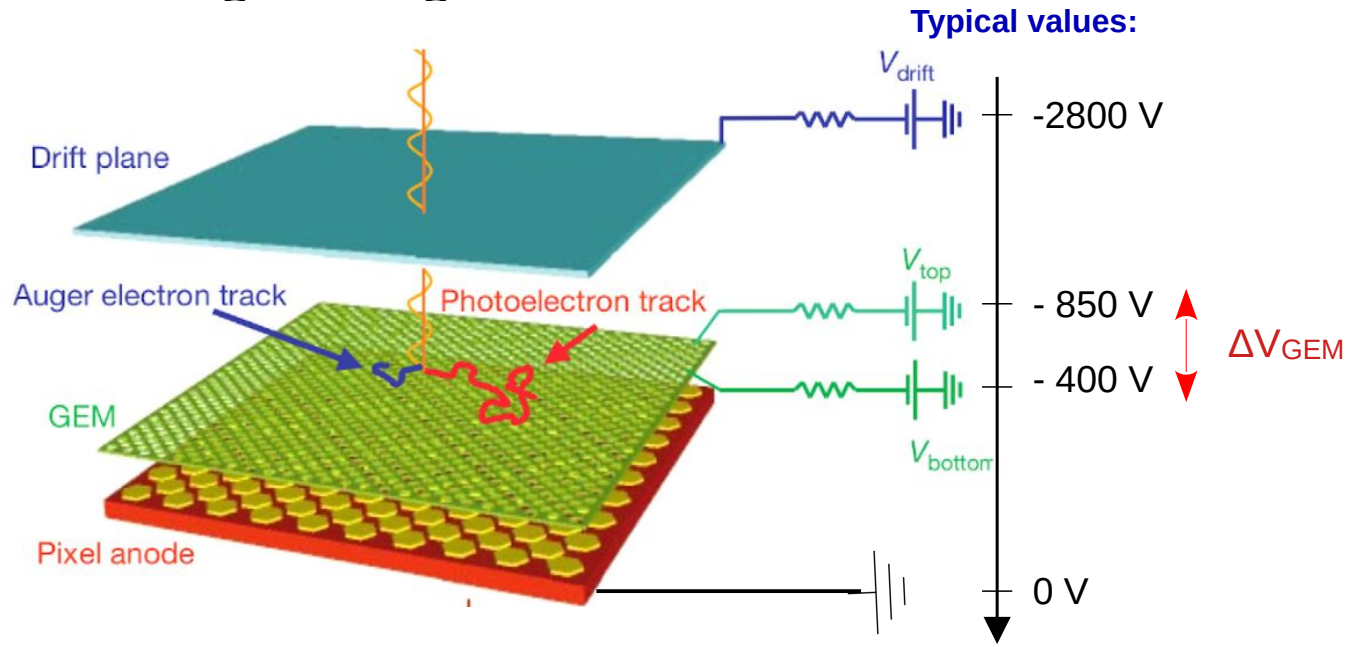
Xtal vertical = 17mm



Xtal vertical = 20mm



GPD: High voltages



Gem gain scales as:

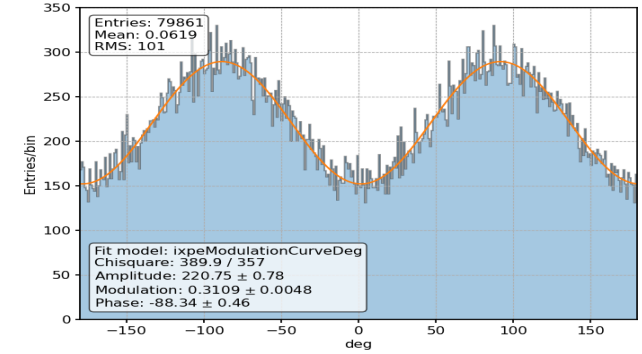
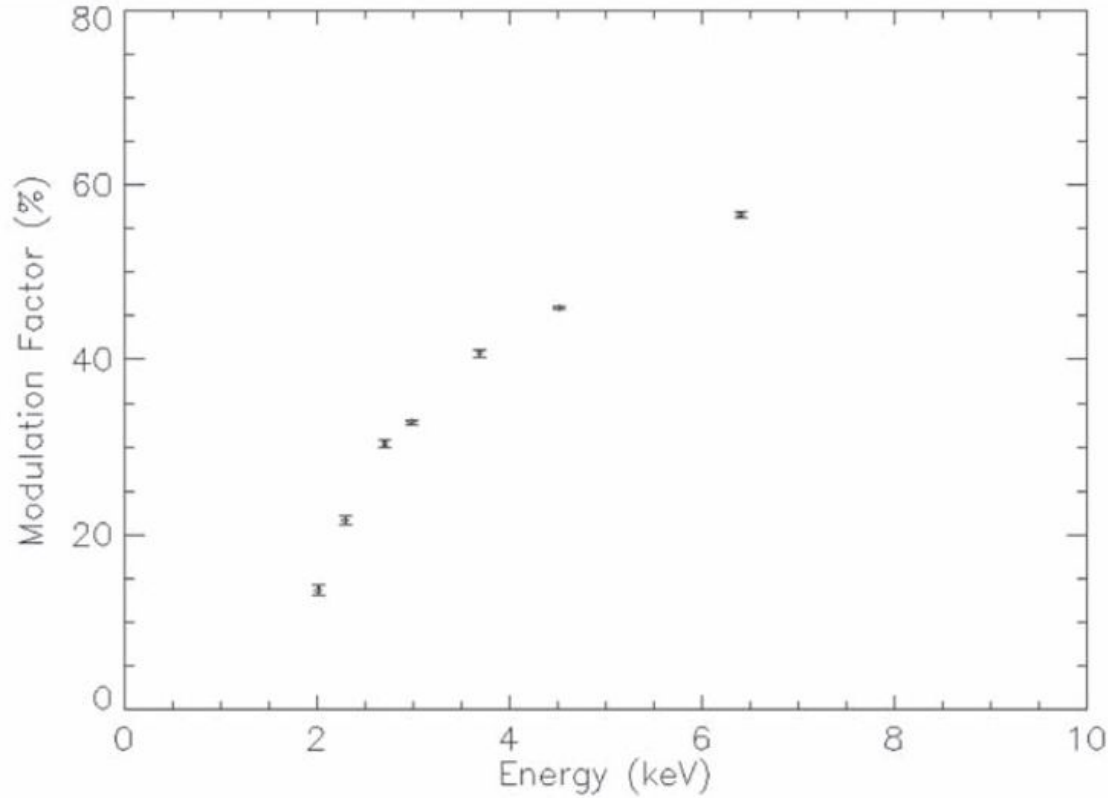
$$G(V) = G_0 e^{\gamma V}$$



In the lab we control the GPD HV levels with an external module.

We set V_{drift} , V_{bottom} , and ΔV_{gem}

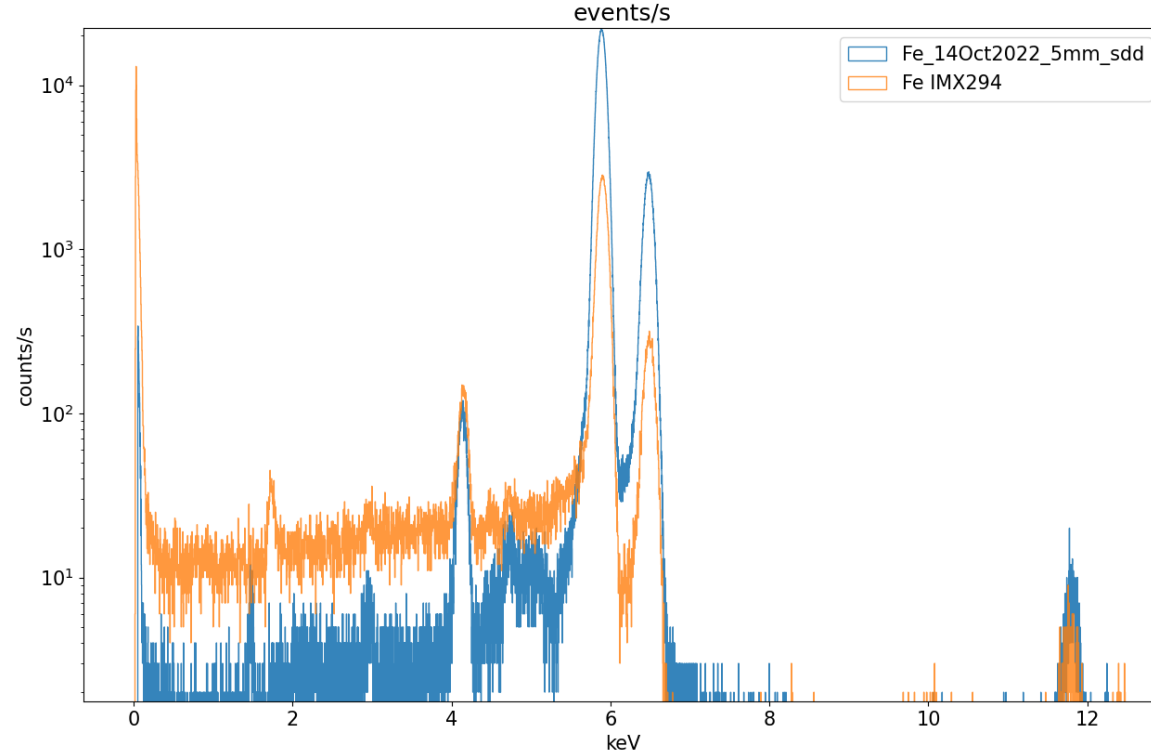
GPD Modulation factor



$$\mathcal{M}(\phi) = A + B \cos^2(\phi - \phi_0),$$

$$M = \frac{\mathcal{M}_{max} - \mathcal{M}_{min}}{\mathcal{M}_{max} + \mathcal{M}_{min}} = \frac{B}{2A + B}.$$

Comparison cmos SDD: rate

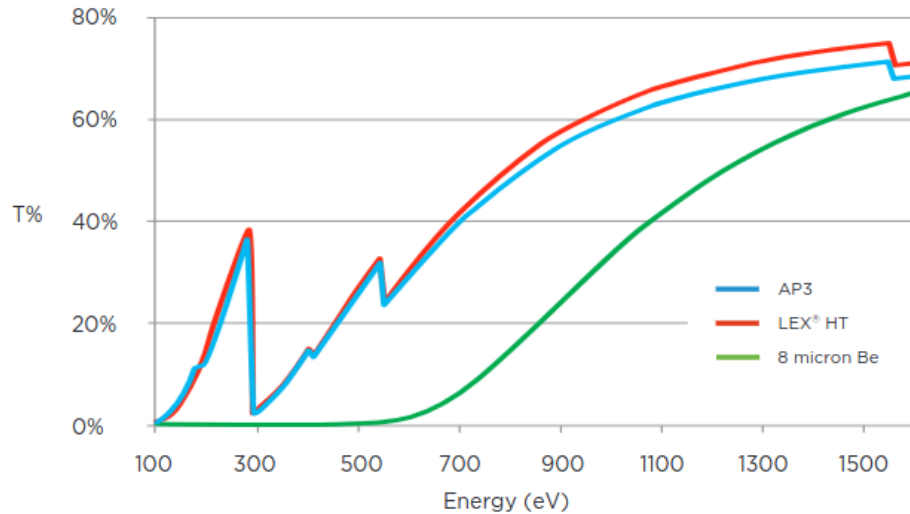


Efficiency with respect to SDD:

Kalpa = 2830/22070 ~ 12% Kbeta → 315/2929 ~ 10%

Luxel window

Large Area X-ray Window



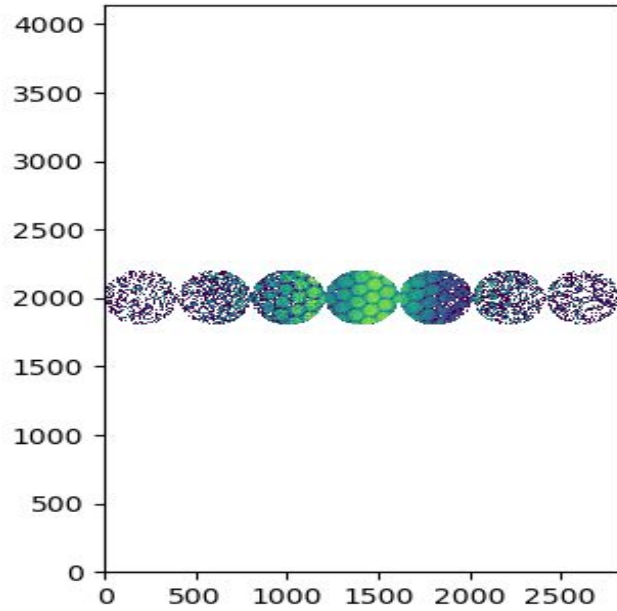
Specifications

Mesh Open Area	80%
Rib Thickness	100 μm
Rib Width	30 μm
Maximum Temperature	100°C
He Leak Rate	<1E-9 mbar-L/sec
Front Side Pressure Limit	1 atm
Maximum Aperture	25mm

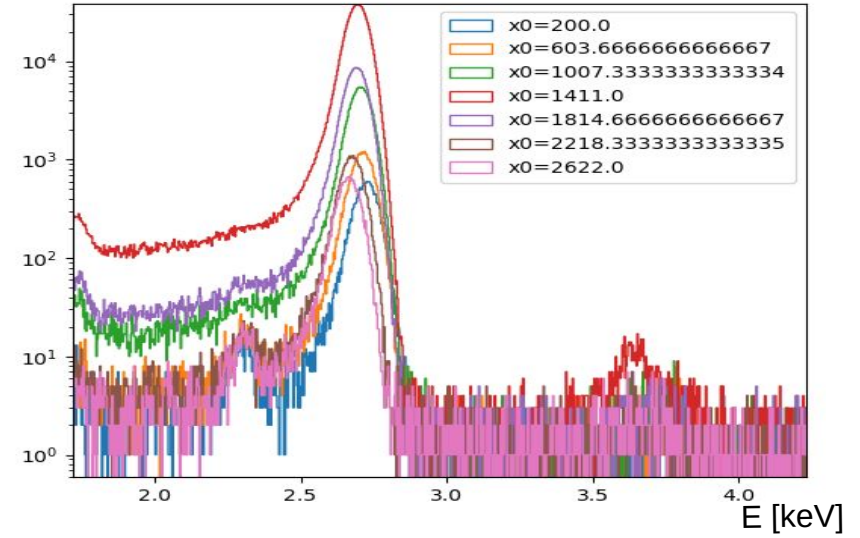


d=16mm

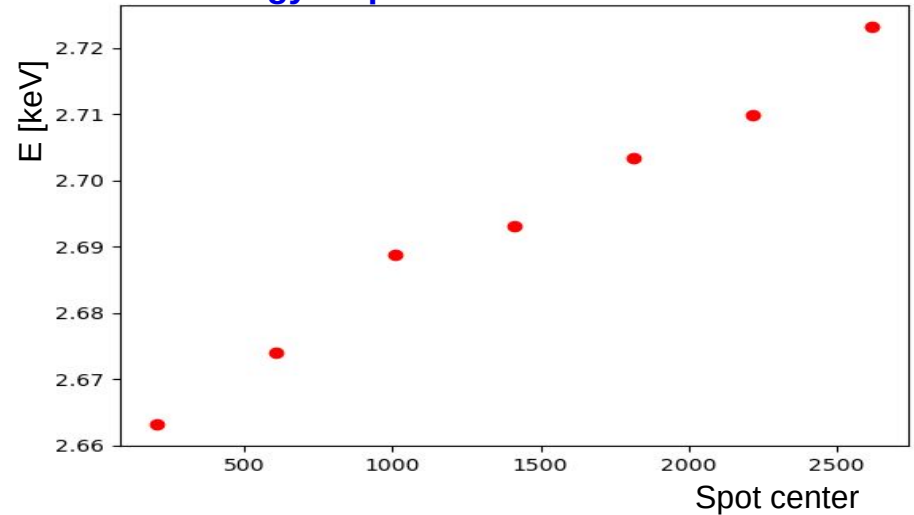
Rh-Ge111: energy-position



As expected different energies are diffracted at different angles



Peak energy vs position



Polarized beam measurements: Rh - Ge111

